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#### What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

## Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

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Product Status	Active
Core Processor	ARM® Cortex®-M4F
Core Size	32-Bit Single-Core
Speed	180MHz
Connectivity	CSIO, EBI/EMI, I <sup>2</sup> C, LINbus, SD, SmartCard, SPI, UART/USART, USB
Peripherals	DMA, I <sup>2</sup> S, LVD, POR, PWM, WDT
Number of I/O	121
Program Memory Size	512KB (512K × 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	128K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 24x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/s6e2gk6hhagv2000a

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



# 1. S6E2G Series Block Diagram





				Product Name								
	Desci	ription	S6E2GM6 S6E2GM8	S6E2GK6 S6E2GK8	S6E2GH6 S6E2GH8	S6E2G36 S6E2G38	S6E2G26 S6E2G28					
Base timer (PWC/Reload timer/PWM/PPG)					16 ch (Max)							
	A/D activatior compare	n 6 ch										
	Input capture	4 ch										
F timer	Free-run timer	3 ch		2 units (Max)								
Σ	Output compare	6 ch										
	Wavefori generato	n r 3 ch										
	PPG	3 ch										
Sm	artcard (I	SO7816)			2 ch (Max)							
QPI	RC		2 ch (Max)									
Dua	al timer		1 unit									
Rea	al-time clo	ock	1 unit									
Wat	tch count	er			1 unit							
CR	C acceler	ator		Yes (fixed)								
Wat	tchdog tir	ner		1 ch (SW) + 1 ch (HW)								
Exte	ernal inte	rrupts			32 pins (Max)+ NMI	× 1						
CSV (clock supervisor) Yes												
LVD (low-voltage detector)			2 ch									
<b>р</b>		High-speed			4 MHz							
Duli		Low-speed			100 kHz							
Deb	oug functi	on			SWJ-DP/ETM/HTM	Л						
Uni	Unique ID Yes											

\*1: Crypto Assist Function is built in following products. S6E2GM6HHA, S6E2GM8HHA, S6E2GM6JHA, S6E2GM8JHA

## Notes:

Because of package pin limitations, not all functions within the device can be brought out to external pins. You must carefully
work out the pin allocation needed for your design.

You must use the port relocate function of the I/O port according to your function use.

- See 12.4.3 Built-In CR Oscillation Characteristics for the accuracy of the built-in CR.





Pin Number		Dia Nama	I/O	Pin State	
LQFP-176	LQFP-144	Pin Name	Туре	Туре	
		P21			
		ADTG_4			
127	103	SIN0_0	l I	K	
		INT27_0			
		CROUT_0			
		P20			
128	104	NMIX	l I	F	
		WKUP0			
129	105	USBVCC1	-	-	
400	400	P82		P	
130	106	UDM1	н	R	
101	107	P83	Ц	P	
131	107	UDP1	п	ĸ	
132	108	VSS	-	-	
133	109	VCC	-	-	
40.4	44.0	P00	-	0	
134	110	TRSTX	E	G	
	111	P01			
135		ТСК	Е	G	
		SWCLK			
400	44.0	P02	F	6	
136	112	TDI	E	G	
		P03			
137	113	TMS	E	G	
		SWDIO			
		P04			
138	114	TDO	E	G	
		SWO			
		P90			
		RTO10_1 (PPG10_1)			
139	-		E	K	
		INT12_1			
			1		
		P91			
		SIN5_1	1		
		RTO11_1			
140	-		E	К	





Pin Number		Din Nome	I/O Circovit	Pin State	
LQFP-176	LQFP-144	Pin Name	Туре	Туре	
		P92			
		SOT5_1			
		(SDA5_1)	-		
141	-	RTO12_1 (PPG12_1)	Е	К	
		TIOB2 1	-		
		INT14_1			
		IC0 VPEN 1			
		P93			
		SCK5 1	-		
		(SCL5_1)			
140		RTO13_1	_	K	
142	-	(PPG13_1)		IX.	
		TIOB3_1			
		INT15_1			
		IC0_RST_1			
		P94		I	
		CTS5_1			
143	-	RTO14_1	Е		
			-		
		P95			
		RTS5 1			
		RT015_1	_		
144	-	- (PPG15_1) E		E	
		TIOB5_1			
		IC0_CIN_1			
145	115	PC0	K	N/	
145	115	E_RXER	Ň	v	
		PC1			
146	116	TIOB6_0	K	V	
		E_RX03			
		PC2			
147	117	TIOA6_0	K	V	
		E_RX02			
		PC3	4		
148	118	TIOB7_0	K	V	
		E_RX01	ļ		
		PC4	1		
149	119	TIOA7_0	K	V	
		E_RX00	ļ		
		PC5	4		
150	120	TIOB14_0	K	V	
		E_RXDV			



# 7. I/O Circuit Type





Туре	Circuit	Remarks
С	N-ch Digital output	<ul> <li>Open drain output</li> <li>CMOS level hysteresis input</li> </ul>



# **Using an External Clock**

When using an external clock as an input of the main clock, set X0/X1 to the external clock input, and input the clock to X0. X1(PE3) can be used as a general-purpose I/O port. Similarly, when using an external clock as an input of the sub clock, set X0A/X1A to the external clock input and input the clock to X0A. X1A (P47) can be used as a general-purpose I/O port.



# Handling When Using Multi-Function Serial Pin as I<sup>2</sup>C Pin

If the application uses the multi-function serial pin as an I<sup>2</sup>C pin, the P-channel transistor of the digital output must be disabled. I<sup>2</sup>C pins need to conform to electrical limitations like other pins, however, and avoid connecting to live external systems with the MCU power off.

## C Pin

Devices in this series contain a regulator. Be sure to connect a smoothing capacitor ( $C_S$ ) for the regulator between the C pin and the GND pin. Please use a ceramic capacitor or a capacitor of equivalent frequency characteristics as a smoothing capacitor. Some laminated ceramic capacitors have a large capacitance variation due to thermal fluctuation. Please select a capacitor that meets the specifications in the operating conditions to use by evaluating the temperature characteristics of the device. A smoothing capacitor of about 4.7  $\mu$ F would be recommended for this series.



## Mode Pins (MD0)

Connect the MD pin (MD0) directly to VCC or VSS pins. Design the printed circuit board such that the pull-up/down resistance stays low, the distance between the mode pins and VCC pins or VSS pins is as short as possible, and the connection impedance is low when the pins are pulled up/down such as for switching the pin level and rewriting the flash memory data. This is important to prevent the device from erroneously switching to test mode as a result of noise.



# 11. Pin Status in Each CPU State

The terms used for pin status have the following meanings:

■ INITX = 0

This is the period when the INITX pin is at the L level.

■ INITX = 1

This is the period when the INITX pin is at the H level.

■ SPL = 0

This is the status that the standby pin level setting bit (SPL) in the standby mode control register (STB\_CTL) is set to 0.

■ SPL = 1

This is the status that the standby pin level setting bit (SPL) in the standby mode control register (STB\_CTL) is set to 1.

Input enabled

Indicates that the input function can be used.

Internal input fixed at 0

This is the status that the input function cannot be used. Internal input is fixed at L.

Hi-Z

Indicates that the pin drive transistor is disabled and the pin is put in the Hi-Z state.

Setting disabled

Indicates that the setting is disabled.

Maintain previous state

Maintains the state that was immediately prior to entering the current mode. If a built-in peripheral function is operating, the output follows the peripheral function. If the pin is being used as a port, that output is maintained.

Analog input is enabled

Indicates that the analog input is enabled.

Trace output

Indicates that the trace function can be used.

GPIO selected

In Deep standby mode, pins switch to the general-purpose I/O port.

Setting prohibition

Prohibition of a setting by specification limitation



Package thermal resistance and maximum permissible power for each package are shown below. The operation is guaranteed maximum permissible power or less for semiconductor devices.

Package	Printed	Thermal Resistance	Maximum Permissible Power (mW)			
i donago	Circuit Board	θja (°C/W)	T <sub>A</sub> = +85 °C	T <sub>A</sub> = +105 °C		
LQS144	Single-layered both sides	48	833	417		
(0.5-mm pitch)	4 layers	33	1212	606		
LQP176	Single-layered both sides	45	889	444		
(0.5-mm pitch)	4 layers	31	1290	645		

#### Table for Package Thermal Resistance and Maximum Permissible Power

### WARNING:

- The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All
  of the device's electrical characteristics are warranted when the device is operated within these ranges.
  Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may
  adversely affect reliability and could result in device failure.
- No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their representatives beforehand.





# 12.3 DC Characteristics

#### 12.3.1 Current Rating

Deveneter	Currente e l	Pin	Conditions		<b>F</b> *4	Va	lue	11	Demerke	
Parameter	Symbol	Name	Conditions	Conditions		Typ* <sup>1</sup>	Max* <sup>2</sup>	Unit	itemarks	
				*5	180 MHz	73	131	mA		
					160 MHz	65	123	mA		
					144 MHz	59	117	mA		
					120 MHz	50	108	mA		
					100 MHz	43	101	mA	*3	
				*6	80 MHz	35	93	mA	When all peripheral	
				0	60 MHz	27	85	mA	CIOCKS are on	
					40 MHz	19	77	mA		
		VCC	Normal operation *7,*8 (PLL)		20 MHz	11	69	mA	-	
					8 MHz	6.9	64	mA		
Power	laa				4 MHz	5.3	63	mA		
supply current	ICC			*5	180 MHz	44	102	mA	-	
					160 MHz	40	98	mA		
					144 MHz	36	94	mA		
					120 MHz	31	89	mA		
					100 MHz	27	85	mA	*3	
				*6	80 MHz	22	80	mA	When all peripheral	
				0	60 MHz	17	75	mA	CIOCKS are off	
					40 MHz	13	71	mA		
					20 MHz	7.9	65	mA		
					8 MHz	5.2	63	mA		
					4 MHz	4.3	62	mA		

 Table 12-1 Typical and Maximum Current Consumption in Normal Operation (PLL), Code Running from Flash Memory (Flash Accelerator Mode and Trace Buffer Function Enabled)

1:  $T_A = +25 \text{ °C}, V_{CC} = 3.3 \text{ V}$ 

2:  $T_J$  = +125 °C,  $V_{CC}$  = 5.5 V

3: When all ports are input and are fixed at 0

4: Frequency is a value of HCLK when PCLK0 = PCLK1 = PCLK2 = HCLK/2

5: When operating flash accelerator mode and trace buffer function (FRWTR.RWT = 11, FBFCR.BE = 1)

6: When operating flash accelerator mode and trace buffer function (FRWTR.RWT = 10, FBFCR.BE = 1)

7: Firmware being executed during data collection for this table is not being accessed from the MainFlash memory."

8: When using the crystal oscillator of 4 MHz (including the current consumption of the oscillation circuit)





Parameter	Symbol	Pin Name	Conditions	Value			Unit	Remarks
			Conditions	Min Typ		Max	onne	Remarks
			$\label{eq:VCC} \begin{array}{l} V_{CC} \geq 4.5 \ \text{V}, \\ I_{OL} = 4 \ \text{mA} \end{array}$	V		0.4	N	
		4 0 - 4	$V_{\rm CC}$ < 4.5 V, I <sub>OL</sub> = 2 mA	VSS	-	0.4	V	
		4 та туре	$\begin{array}{l} \text{ETHV}_{\text{CC}} \geq 4.5 \text{ V}, \\ I_{\text{OL}} = 4 \text{ mA} \end{array} \end{array} \label{eq:electropy}$			0.4		
			$\begin{array}{l} \text{RTHV}_{\text{CC}} < 4.5 \text{ V}, \\ \text{I}_{\text{OL}} = 2 \text{ mA} \end{array}$	VSS	-	0.4	V	
			$\label{eq:V_CC} \begin{array}{l} V_{CC} \geq 4.5 \ \text{V}, \\ I_{OL} = 8 \ \text{mA} \end{array}$	Mar		0.4	N	
		8 m	V <sub>CC</sub> < 4.5 V, I <sub>OL</sub> = 4 mA	VSS	-	0.4	v	
		o ma type	$\begin{array}{l} \text{ETHV}_{\rm CC} \geq 4.5 \text{ V,} \\ I_{\rm OL} = 8 \text{ mA} \end{array} \end{array} \label{eq:electropy}$	Mag		0.4	V	
L level output voltage	$V_{OL}$		$\begin{array}{l} \text{RTHV}_{\text{CC}} < 4.5 \text{ V,} \\ \text{I}_{\text{OL}} = 4 \text{ mA} \end{array}$	VSS	-	0.4	v	
		12 mA type The pin doubled as USB I/O	$\label{eq:V_CC} \begin{array}{l} \geq 4.5 \text{ V}, \\ I_{\rm OL} = 12 \text{ mA} \end{array}$	V		0.4	V	
			$V_{\rm CC}$ < 4.5 V, $I_{\rm OL}$ = 8 mA	VSS	-	0.4		
			$\label{eq:USBV} \begin{array}{l} USBV_{\rm CC} \geq 4.5 \ \text{V}, \\ I_{\rm OL} = 18.5 \ \text{mA} \end{array}$	Mag		0.4	V	*1
			$\label{eq:USBV} \begin{array}{l} USBV_{\rm CC} < 4.5 \text{ V}, \\ I_{\rm OL} = 10.5 \text{ mA} \end{array}$	VSS	-	0.4	v	I
			$\label{eq:VCC} \begin{array}{l} V_{CC} \geq 4.5 \ \text{V}, \\ I_{OL} = 4 \ \text{mA} \end{array}$					
		The pin doubled as I <sup>2</sup> C Fm+	V <sub>CC</sub> < 4.5 V, I <sub>OL</sub> = 3 mA	Vss	-	0.4	V	AI GPIO
			$V_{CC} \leq 4.5 \text{ V},$ $I_{OL} = 20 \text{ mA}$					At I <sup>2</sup> C Fm+
Input leak current	IIL	-	-	- 5	-	+ 5	μA	
Pull-up	Р	Dull up nin	$V_{CC} \geq 4.5 \ V$	25	50	100	10	
resistor value	<b>R</b> PU	Pull-up pin	$V_{\rm CC}$ < 4.5 V	30	80	200	K12	
Input capacitance	Cin	Other than VCC, USBVCC0, USBVCC1, ETHVCC, VSS, AVCC, AVSS, AVRH	-	-	5	15	pF	

1: USBV<sub>CC</sub>0 and USBV<sub>CC</sub>1 are described as USBV<sub>CC</sub>.









# When Using Synchronous Serial Chip Select (SCINV = 1, CSLVL = 1)

 $(V_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = 0V)$ 

Deremeter	Symbol	Conditions	Vcc <	4.5 V	V <sub>cc</sub> ≥	Unit	
Falameter	Symbol	Conditions	Min	Max	Min	Max	Unit
SCS↓→SCK↓ setup time	t <sub>CSSI</sub>		(*1)-50	(*1)+0	(*1)-50	(*1)+0	ns
SCK↑→SCS↑ hold time	t <sub>CSHI</sub>	Internal shift clock	(*2)+0	(*2)+50	(*2)+0	(*2)+50	ns
SCS deselect time	t <sub>CSDI</sub>	operation	(*3)-50 +5t <sub>CYCP</sub>	(*3)+50 +5t <sub>СҮСР</sub>	(*3)-50 +5t <sub>СҮСР</sub>	(*3)+50 +5t <sub>СҮСР</sub>	ns
SCS↓→SCK↓ setup time	tcsse		3tcycp+30	-	3tcycp+30	-	ns
SCK↑→SCS↑ hold time	tcshe		0	-	0	-	ns
SCS deselect time	t <sub>CSDE</sub>	External shift clock	3t <sub>CYCP</sub> +30	-	3t <sub>CYCP</sub> +30	-	ns
SCS ↓ →SOT delay time	tdse	operation	-	40	-	40	ns
SCS ↑ →SOT delay time	tDEE		0	-	0	-	ns

(\*1): CSSU bit valuexserial chip select timing operating clock cycle [ns]

(\*2): CSHD bit valuexserial chip select timing operating clock cycle [ns]

(\*3): CSDS bit valuexserial chip select timing operating clock cycle [ns]

#### Notes:

- tcycp indicates the APB bus clock cycle time. For more information about the APB bus number to which the multi-function serial is connected, see 1. S6E2G Series Block Diagram in this data sheet.
- For more information about CSSU, CSHD, CSDS, and the serial chip select timing operating clock, see FM4 Family Peripheral Manual Main Part (002-04856).
- When the external load capacitance  $C_L = 30 \text{ pF}$ .









# 12.4.13 External Input Timing

 $(V_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = 0V)$ 

Deremeter	Sympol	Din Nome	Conditions	Value		110:4	Bomarka	
Parameter	Symbol	Pin Name	Conditions	Min	Max	Unit	Remarks	
		ADTGx					A/D converter trigger input	
		FRCKx	-	2t <sub>CYCP</sub> *1	-	ns	Free-run timer input clock	
		lcxx					Input capture	
Input pulse	Input pulse	DTTIxX	-	2t <sub>CYCP</sub> *1	-	ns	Waveform generator	
width		INT00 to INT31, NMIX		2t <sub>CYCP</sub> + 100 <sup>*1</sup>	-	ns	External interrupt,	
				500 <sup>*2</sup>	-	ns	NMI	
		WKUPx	-	500 <sup>*3</sup>	-	ns	Deep standby wake up	

1: t<sub>CYCP</sub> indicates the APB bus clock cycle time except stop when in Stop mode, in Timer mode. For more information about the APB bus number to which the A/D converter, multi-function timer, and external interrupt are connected, see 1. S6E2G Series Block Diagram in this data sheet.

2: When in Stop mode, in Timer mode

3: When in Deep Standby RTC mode, in Deep Standby Stop mode











# 12.8 MainFlash Memory Write/Erase Characteristics

 $(V_{CC} = 2.7V \text{ to } 5.5V)$ 

Parameter		Value			Unit	Domorika	
		Min	Тур	Мах	Unit	Remarks	
Contax areas time	Large Sector	-	0.7	3.7	s	Includes write time prior to internal	
Sector erase time	Small Sector	-	0.3	1.1	S	erase	
Half word (16-bit)	Write cycles < 100 times		12	100		Not including system-level overhead	
write time	Write cycles > 100 times	-		200	μs	time	
Chip erase time*		-	13.6	68	S	Includes write time prior to internal erase	

 $\ensuremath{^*\!:}$  It indicates the chip erase time of 1MB MainFlash memory

For devices with 1.5 MB or 2 MB of MainFlash memory, two erase cycles are required.

See 3.2.2 Command Operating Explanations and 3.3.3 Flash Erase Operation in this product's Flash Programming Manual for the detail.

# Write Cycles and Data Retention Time

Erase/Write Cycles (Cycle)	Data Retention Time (Year)
1,000	20*
10,000	10*
100,000	5*

\*: This value comes from the technology qualification (using Arrhenius equation to translate high temperature acceleration test result into average temperature value at + 85°C).



# 12.9 Standby Recovery Time

### 12.9.1 Recovery Cause: Interrupt/WKUP

The time from the interrupt occurring to the time of program operation start is shown.

# **Recovery Count Time**

 $(V_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = 0V)$ 

Parameter	Symbol	Value		1114	Demarka
		Тур	Max*	Unit	Remarks
Sleep mode		HCLK×1		μs	
High-speed CR Timer mode Main Timer mode PLL Timer mode	ticnt	40	80	μs	
Low-speed CR Timer mode		450	900	μs	
Sub Timer mode		896	1136	μs	
RTC mode Stop mode (High-speed CR/Main/PLL Run mode return)		316	581	μs	
RTC mode Stop mode (Low-speed CR/sub Run mode return)		270	540	μs	
Deep Standby RTC mode with RAM retention Deep Standby Stop mode with RAM retention		365	667	μs	without RAM retention
		365	667	μs	with RAM retention

\*: The maximum value depends on the built-in CR accuracy.

# Example of Standby Recovery Operation (when in External Interrupt Recovery\*)



<sup>\*:</sup> External interrupt is set to detecting fall edge.





### Example of Standby Recovery Operation (when in Internal Resource Interrupt Recovery\*)

\*: Depending on the standby mode, interrupt from the internal resource is not included in the recovery cause.

#### Notes:

- The return factor is different in each low-power consumption mode. See Chapter 6: Low Power Consumption mode and Operations of Standby modes in FM4 Family Peripheral Manual Main Part (002-04856).
- The recovery process is unique for each operating mode. See Chapter 6: Low Power Consumption mode in FM4 Family Peripheral Manual Main Part (002-04856).



# 14. Package Dimensions

